

**Notice of References Cited**

Application/Control No.

10/779,904

Applicant(s)/Patent Under  
Reexamination  
ISHIDA ET AL.

Examiner

OSCAR A. LOUIE

Art Unit

2436

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,828,815	12-2004	Ishida et al.	324/765
*	B	US-6,801,049	10-2004	Ishida et al.	324/765
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Quiescent power supply current measurement for CMOS IC defect detection," Hawkins et al., Industrial Electronics, IEEE Transactions on, Volume: 36, Issue: 2, May 1989.
	V	"Defect detection with transient current testing and its potential for deep submicron CMOS ICs," Sachdev et al., Test Conference, 1998. Proceedings., International, 18-23 Oct 1998.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.